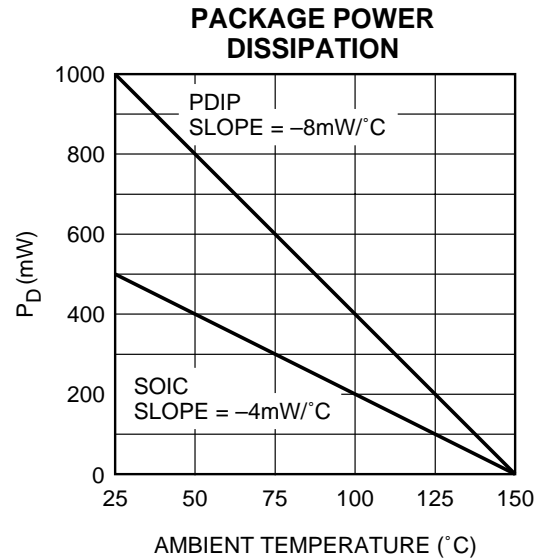


ABSOLUTE MAXIMUM RATINGS

Supply Voltage	+22V
Input Voltage, IN A or IN B	$V_{DD}+0.3V$ to GND-5.0V
Maximum Chip Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering, 10 sec)	+300°C
Package Thermal Resistance	
PDIP $R_{\theta J-A}$	125°C/W
PDIP $R_{\theta J-C}$	42°C/W
SOIC $R_{\theta J-A}$	250°C/W
SOIC $R_{\theta J-C}$	75°C/W
Operating Temperature Range	
Both Versions	-40°C to +85°C
Power Dissipation	
Plastic	1000mW
SOIC	500mW

Static-sensitive device. Unused devices must be stored in conductive material. Protect devices from static discharge and static fields. Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operation sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



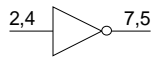
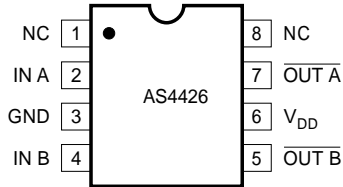
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ELECTRICAL CHARACTERISTICS $T_A = +25^\circ\text{C}$ with $4.5V \leq V_{DD} \leq 18V$, unless otherwise specified.

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT	TEST CONDITIONS
INPUT						
V_{IH}	Logic 1 High Input Voltage	2.4	-	-	V	
V_{IL}	Logic 0 Low Input Voltage	-	-	0.8	V	
I_{IN}	Input Current	-1	-	1	μA	$0V \leq V_{IN} \leq V_{DD}$
OUTPUT						
V_{OH}	High Output Voltage	$V_{DD}-0.025$	-	-	V	
V_{OL}	Low Output Voltage	-	-	0.025	V	
R_O	Output Resistance	-	7	10	Ω	$V_{DD} = 18V, I_o = 10mA$
I_{PK}	Peak Output Current	-	1.5	-	A	
I_{REV}	Latch-Up Protection Withstand Reverse Current	>0.5	-	-	A	Duty Cycle $\leq 2\%$ $t \leq 300\mu\text{s}$
SWITCHING TIME (Note 1)						
t_R	Rise Time	-	25	30	ns	Figure 1
t_F	Fall Time	-	25	30	ns	Figure 1
t_{D1}	Delay Time	-	-	30	ns	Figure 1
t_{D2}	Delay Time	-	-	50	ns	Figure 1
POWER SUPPLY						
I_S	Power Supply Current	-	-	4.5	mA	$V_{IN} = 3V$ (Both Inputs)
		-	-	0.4	mA	$V_{IN} = 0V$ (Both Inputs)

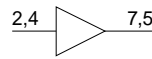
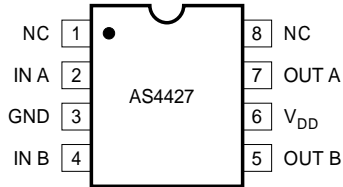
Note: 1. Switching times are guaranteed by design.

PIN CONFIGURATIONS

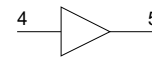
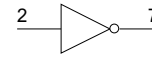
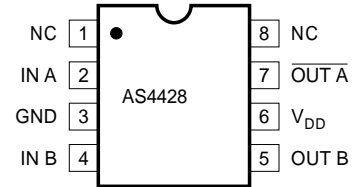


INVERTING

NC = NO INTERNAL CONNECTION



NONINVERTING



DIFFERENTIAL

NOTE: SOIC pinout is identical to DIP.

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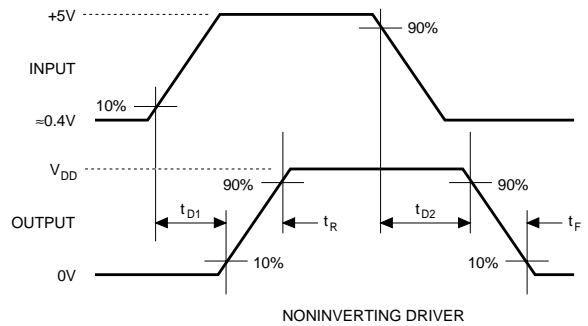
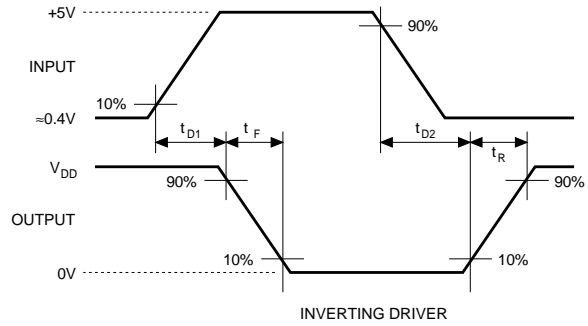
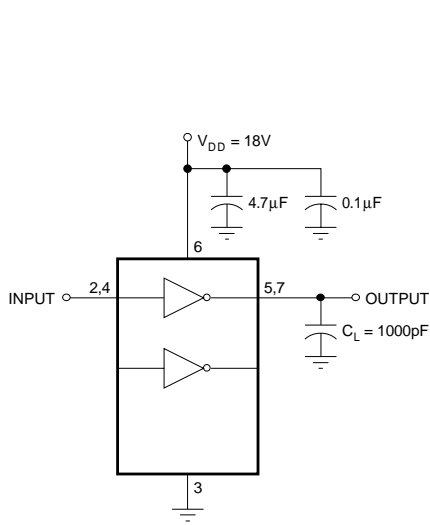
ELECTRICAL CHARACTERISTICS

Specifications measured over temperature range with $4.5V \leq V_{DD} \leq 18V$, unless otherwise specified.

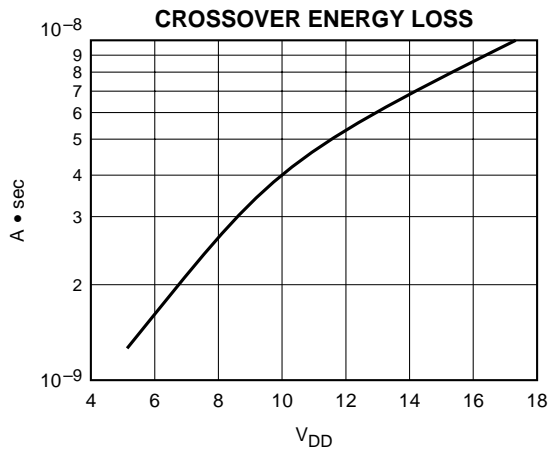
SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT	TEST CONDITIONS
INPUT						
V_{IH}	Logic 1 High Input Voltage	2.4	-	-	V	
V_{IL}	Logic 0 Low Input Voltage	-	-	0.8	V	
I_{IN}	Input Current	-1	-	1	μA	$0V \leq V_{IN} \leq V_{DD}$
OUTPUT						
V_{OH}	High Output Voltage	$V_{DD}-0.025$	-	-	V	
V_{OL}	Low Output Voltage	-	-	0.025	V	
R_O	Output Resistance	-	9	12	Ω	$V_{DD} = 18V, I_O = 10mA$
I_{PK}	Peak Output Current	-	1.5	-	A	
I_{REV}	Latch-Up Protection Withstand Reverse Current	>0.5	-	-	A	Duty Cycle $\leq 2\%$ $t \leq 300\mu s$
SWITCHING TIME (Note 1)						
t_R	Rise Time	-	-	40	ns	Figure 1
t_F	Fall Time	-	-	40	ns	Figure 1
t_{D1}	Delay Time	-	-	40	ns	Figure 1
t_{D2}	Delay Time	-	-	60	ns	Figure 1
POWER SUPPLY						
I_S	Power Supply Current	-	-	8	mA	$V_{IN} = 3V$ (Both Inputs)
		-	-	0.6	mA	$V_{IN} = 0V$ (Both Inputs)

Note: 1. Switching times are guaranteed by design.

FIGURE 1. SWITCHING TIME TEST CIRCUIT



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NOTE: The values on this graph represent the loss seen by both drivers in a package during one complete cycle. For a single driver, divide the stated values by 2. For a single transition of a single driver, divide the stated value by 4.

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